

### Content



#### Company



#### What can be tested, and how?

Different types of test points
Device-under-test
specification
Complete set-up

#### Mobile network testing

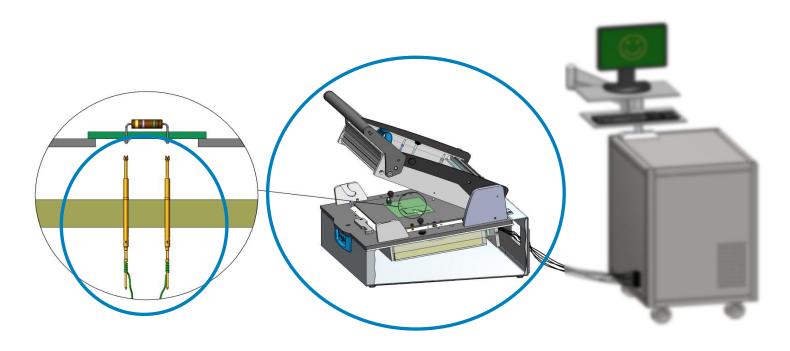
Test solutions
Antenna feed testing
Future Technologies

#### Conclusion



## Welcome to INGUN

#### No. 1 Manufacturer of Testing Equipment



Test Probes – Connection between PCB and test fixture

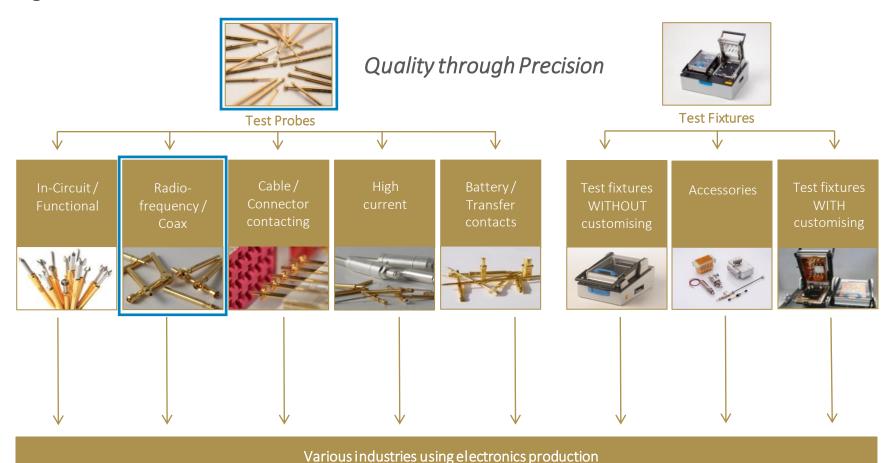
**Test Fixture** – Connection between test probe and test system

Test system



## One-stop Custom-made Test Solutions

#### Eight test areas:





## What is Challenging in RF and High Speed Testing?

#### Main issues:

- For mass production testing, automated test solutions are required
- Rising frequencies and data rates requires more accurate mechanics
- High-density packaging on electronical boards means less space for test points



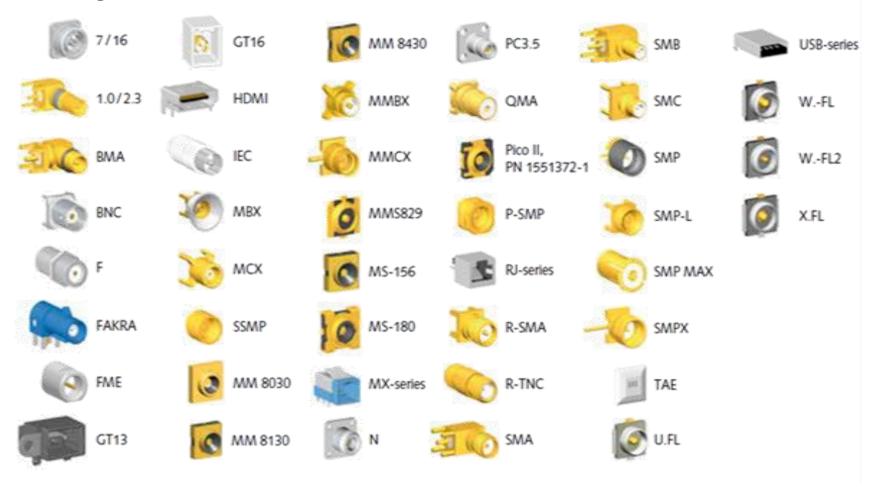
Large assortment of RF probes up to 20 GHz - unrivaled range

- PCB contacting in grids up to 0.5 mm (= 20 Mil)
- RF probes for all standard connectors from "A" like AMC to "X" like X.FL
- Automotive connectors, such as FAKRA, HSD, etc.
- High return loss with low insertion loss
- Integrated technologies, such as filters and attenuators
- Digital test solution, e.g., USB up to 5 GBit/s



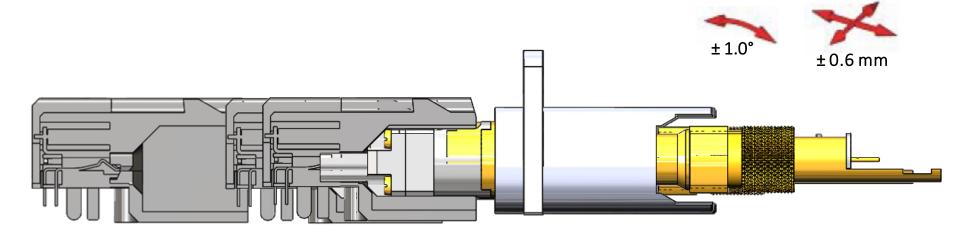


#### Contacting standard connectors

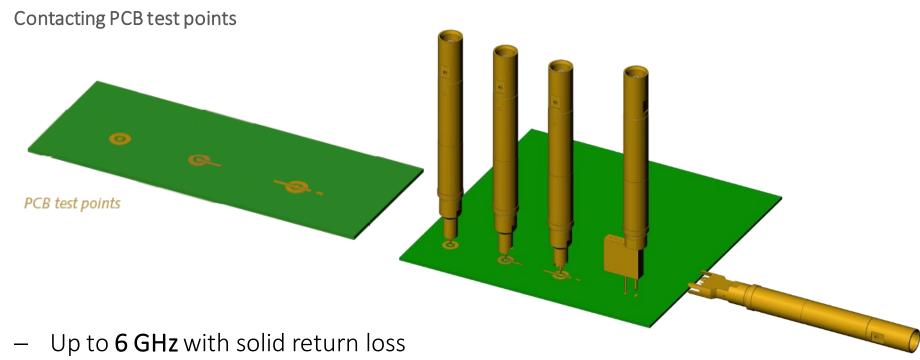




Contacting example: HFS-821 contacting USB mini plug



- 1. 'Floating' test probe is aligned in the connector
- 2. Contact is made
- 3. Decompress the complete unit to achieve stable, reliable contact



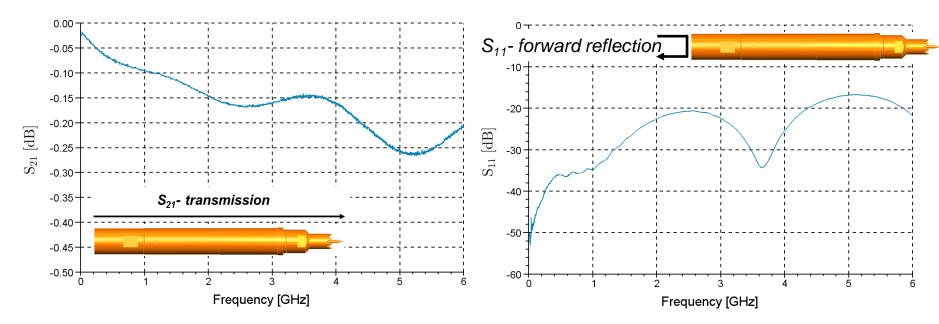
- Test solutions with integrated attenuator is available to achieve better return loss



Device-under-test specification

#### Analog specification:

- VNA (scattering parameters e.g.  $S_{11}$  and  $S_{21}$ )

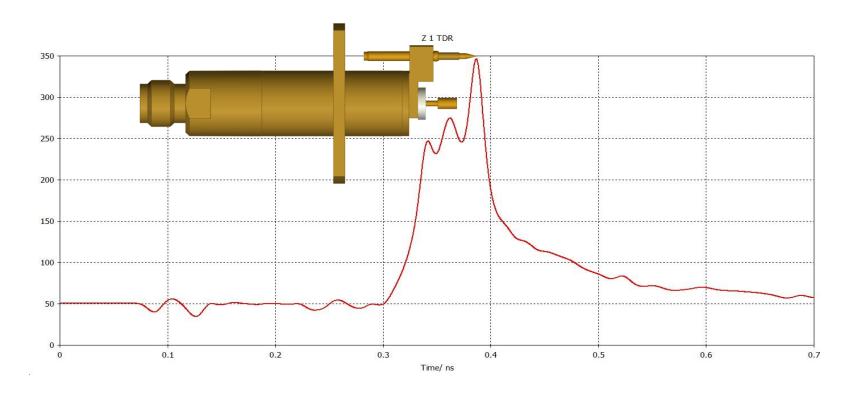


- Spectrum analyser (amplitude vs. frequency)
- Power meter (amplitude)



Device-under-test specification

Oscilloscope (amplitude and phase) → Time Domain Reflectometry (TDR)

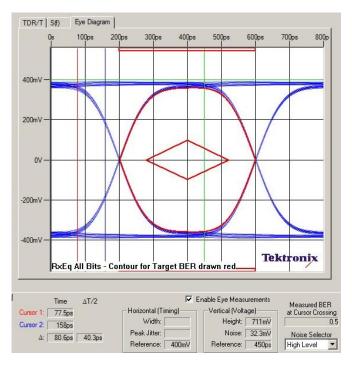


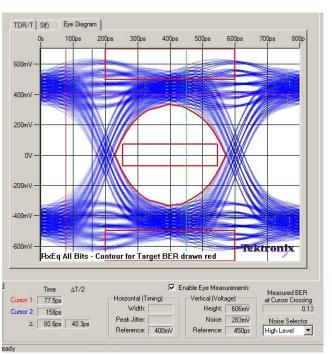


Device-under-test specification

#### Digital specification:

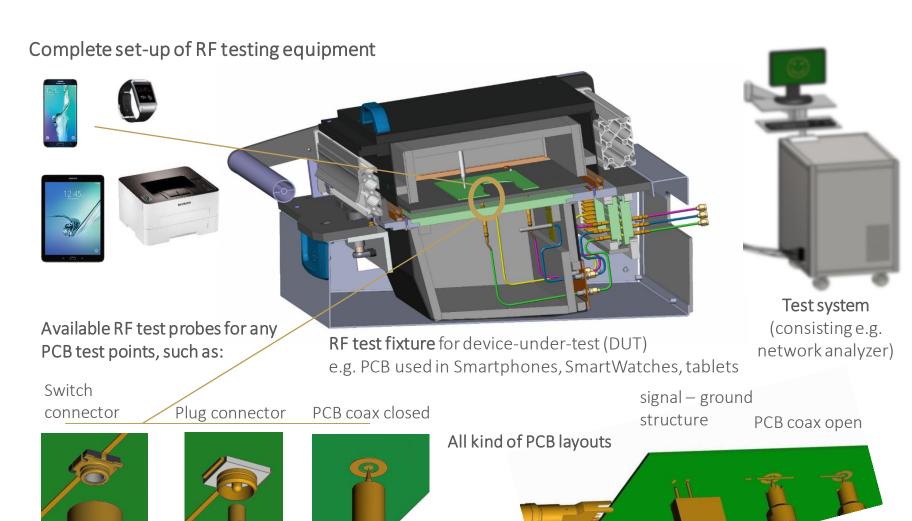
- MOI specifies e.g. impedance, propagation delay, skew, attenuation, NEXT, FEXT
- Eye diagram tests carry information about <u>jitter</u> and <u>amplitude</u>







RF Technology Days 2016 – INGUN Prüfmittelbau GmbH – Stephan Grensemann





Using wireless or RF communication features for all industry standards, connectors, switches and

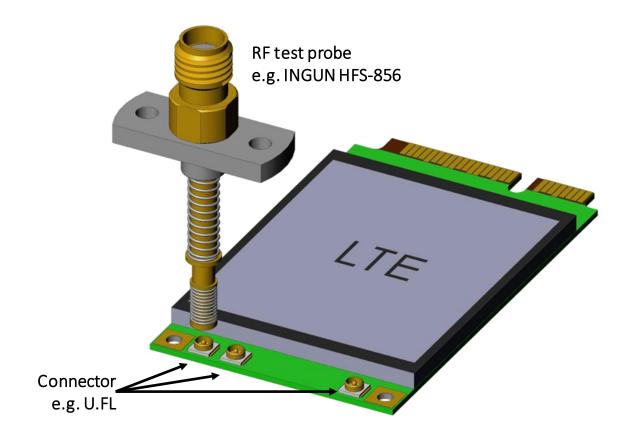
customized test points





Using antenna connector as test point

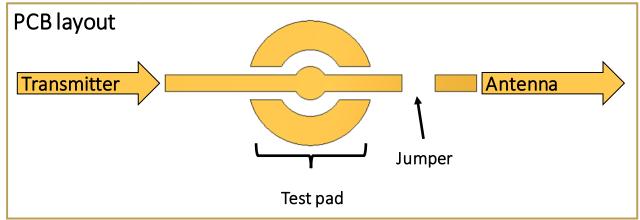
1. Case: Antenna can be connected after testing

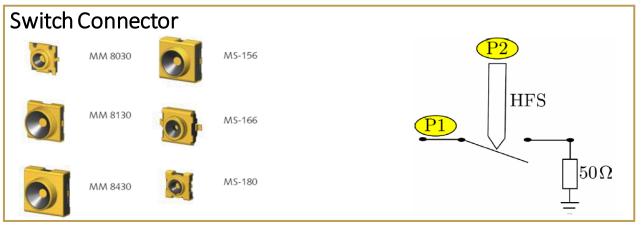




PCB layout vs. switch connector

2. Case: Using e.g., ship antennas on Printed Circuit Boards (PCBs)

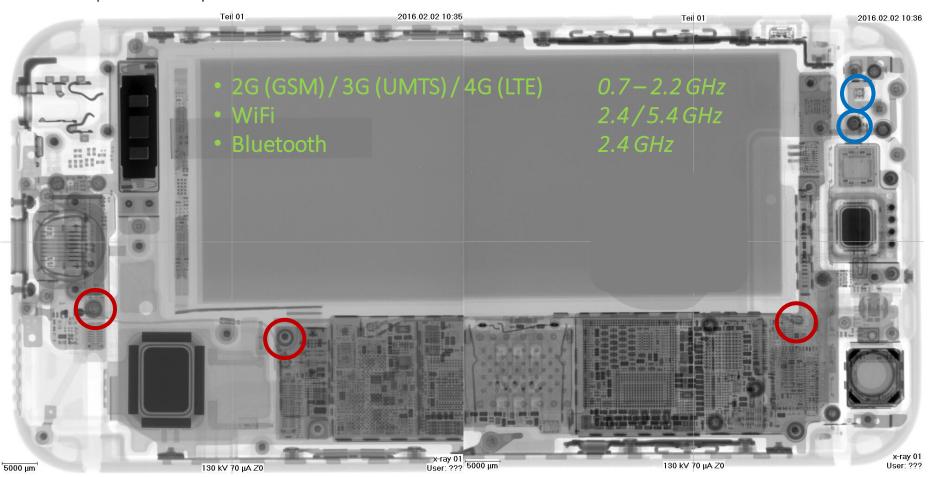






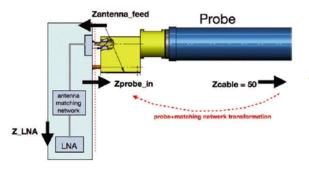
sub-miniature connector switch connector

Mobile phone example

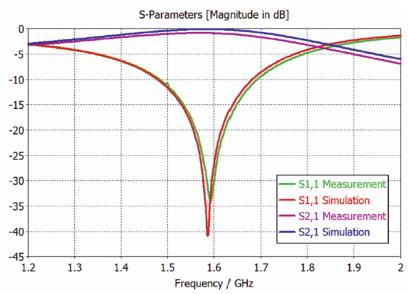




#### Impedance-matching probe for antenna feed testing

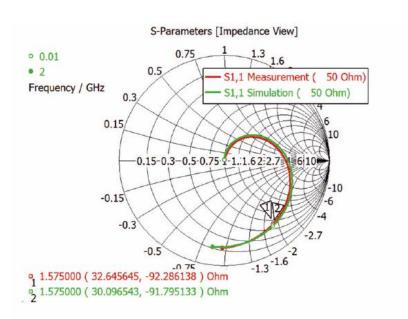


Example for the use of a RF test probe with narrow band matching network





RF test probe with narrow band matching network



Comparision of simulation and measurement: The transformation shown in the Smith chart



Future Technologies

## What's coming next?







## Conclusion

- A great assortment of different RF test probes are already available
- RF and digital signals can be measured
- Developers of electronical test boards always struggle with test points. Please challenge us!
- For future technologies, such as 5G or high-speed digital testing, please don't miss the **electronica 2016** tradeshow in Munich!





## Thank you for your attention

Need more advice?

Don't hesitate to contact us.

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